

Name: Solution MT1 - Fall 2016

EE303 - Midterm Exam #1

**Closed Book:**

One 8.5"x11" sheet of handwritten notes permitted  
Calculator permitted

**Important Notes:**

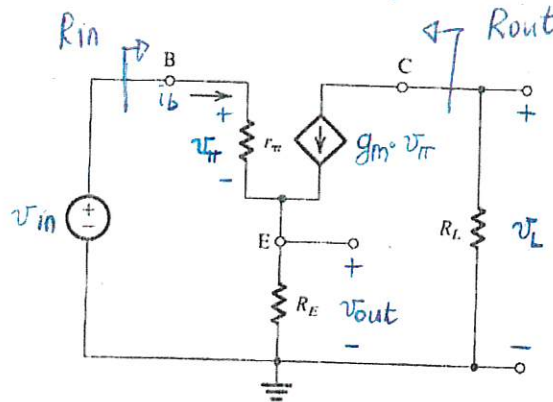
- Read each problem completely and thoroughly
- Summarize all your answers in the boxes provided on these exam sheets
- Make sure to mark the units on your answers !
- Do all your work on the exams sheets provided. If you use any additional sheets, please turn them in, so we can consider all work for partial credit
- Do not forget to put your name in the space above

Problem #	Points	Score
1	30	
2	5	
3	5	
4	15	
5	5	
6	20	
<b>TOTAL</b>	<b>80</b>	

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Problem 1 [30 pts]

Given the circuit in Fig.1 find an expression for  $R_{in}$ ,  $R_{out}$ , and  $A_v = v_{out}/v_{in}$



$$v_{out} = R_E \left( \frac{v_{\pi}}{r_{\pi}} + g_m v_{\pi} \right)$$

$$v_{in} = v_{\pi} + v_{out} \rightarrow$$

$$v_{\pi} = v_{in} - v_{out}$$

Figure 1

$R_{in}$	$\approx r_{\pi} (1 + g_m R_E)$
$R_{out}$	$= \infty$
$A_v$	$\approx 1$

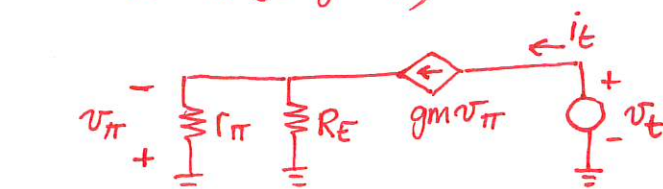
$$v_{out} = v_{\pi} \left( \frac{R_E}{r_{\pi}} + g_m R_E \right) = v_{in} \left( \frac{R_E + g_m R_E r_{\pi}}{r_{\pi}} \right) - v_{out} \left( \frac{R_E + g_m R_E r_{\pi}}{r_{\pi}} \right)$$

$$v_{out} \left( 1 + \frac{R_E + g_m R_E r_{\pi}}{r_{\pi}} \right) = v_{in} \frac{R_E + g_m R_E r_{\pi}}{r_{\pi}}$$

$$\frac{v_{out}}{v_{in}} = \frac{R_E + g_m R_E r_{\pi}}{r_{\pi} + R_E + g_m R_E r_{\pi}} = \frac{R_E (1 + g_m r_{\pi})}{r_{\pi} + R_E (1 + g_m r_{\pi})} \approx 1$$

$$R_{in} = \frac{v_{in}}{i_b} = \frac{v_{\pi} + R_E g_m v_{\pi} + (v_{\pi}/r_{\pi}) \cdot R_E}{v_{\pi}/r_{\pi}} = r_{\pi} (1 + R_E g_m + R_E/r_{\pi}) \approx$$

$$\approx r_{\pi} (1 + g_m R_E)$$



$$R_{out} = v_t / i_t = \infty$$

$$i_t = g_m \cdot v_{\pi}$$

$$v_{\pi} = -i_t (r_{\pi} \parallel R_E) = -i_t \cdot R$$

positive quantity

$$i_t = -i_t g_m R \rightarrow i_t (1 + g_m R) = 0 \rightarrow$$

$$\rightarrow i_t = 0$$

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Problem 2 [5 pts]

A silicon wafer is doped with donors at a concentration of  $N_D = 10^{15} \text{ cm}^{-3}$ . Assuming  $n_i$  at room temperature is  $10^{10} \text{ cm}^{-3}$

(a) What is the electron concentration  $n_o$  ( $\text{cm}^{-3}$ ) at room temperature?

(b) What is the holes concentration  $p_o$  ( $\text{cm}^{-3}$ ) at room temperature?

(a) $n_o =$	$10^{15} \text{ cm}^{-3}$
(b) $p_o =$	$10^5 \text{ cm}^{-3}$

$$p_o \approx \frac{n_i^2}{n_o} = \frac{10^{20}}{10^{15}}$$

Problem 3 [5 pts]

Using the fact that a silicon diode has  $I_S = 10^{-14} \text{ A}$  at  $25^\circ\text{C}$  and that  $I_S$  increases by 15% per  $^\circ\text{C}$  rise in temperature, find the value of  $I_S$  at  $125^\circ\text{C}$ .

$I_S$ at $125^\circ\text{C} =$	$117 \times 10^{-10} \text{ A}$
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$$\begin{aligned} I_S(125^\circ\text{C}) &= I_S(25^\circ\text{C}) \times 1.15^{\Delta T} = \\ &= 10^{-14} \times 1.15^{100} \approx 117 \times 10^{-10} \text{ A} \end{aligned}$$

$$\Delta T = T - T_0$$

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Problem 4 [15 pts]

Consider the circuit shown in Fig. 2. A string of three diodes is used to provide a constant voltage of about 2.1 V. We want to calculate the percentage change in this regulated voltage caused by

- (a) a  $\pm 10\%$  change in the power-supply voltage without the load  
 (b) a  $\pm 10\%$  change in the power-supply voltage with a load of 1-k $\Omega$  connected

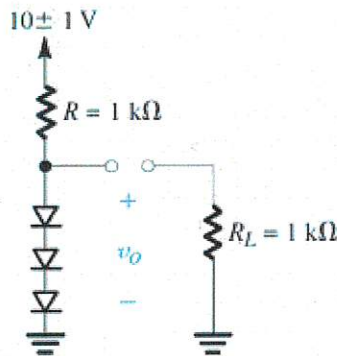


Figure 2

(a) $\Delta V_o / \Delta V_{\text{supply}} =$	9.51 mV/V
(b) $\Delta V_o / \Delta V_{\text{supply}} =$	12.5 mV/V

without load :

$$I_D = \frac{10 - 2.1V}{1k\Omega} = 7.9 \text{ mA}$$

$$r_d = \frac{V_T}{I_D} = \frac{25 \text{ mV}}{7.9 \text{ mA}} \approx 3.2 \Omega$$

$$\frac{\Delta V_o}{\Delta V_{\text{supply}}} = \frac{3 \times r_d}{R + 3r_d} = \frac{9.6}{9.6 + 1000} \approx 9.51 \frac{\text{mV}}{\text{V}}$$

with load

the operating point changes:  $I_{R_L} = \frac{2.1V}{1k\Omega} = 2.1 \text{ mA}$

$$I_R = \frac{10 - 2.1}{1k\Omega} = 7.9 \text{ mA}$$

$$I_D = I_R - I_{R_L} = 5.8 \text{ mA} \rightarrow r_d = \frac{V_T}{I_D} \approx 4.3 \Omega$$

$$\frac{\Delta V_o}{\Delta V_{\text{supply}}} = \frac{3r_d \parallel R_L}{3r_d \parallel R_L + R} \approx 12.5 \text{ mV/V}$$

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*Problem 5 [5 pts]*

For the circuit in Figure 3, utilizing an ideal diode, sketch the steady state output for the input shown. Label the most positive and most negative output levels.

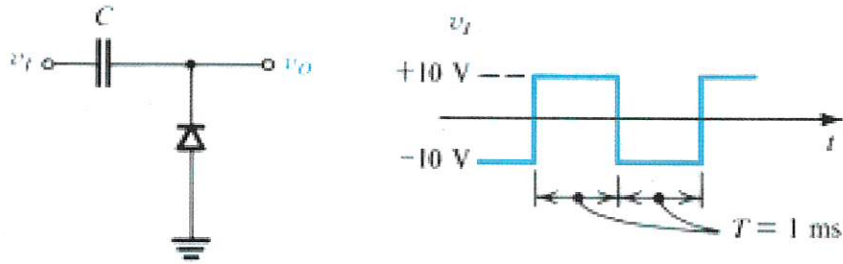
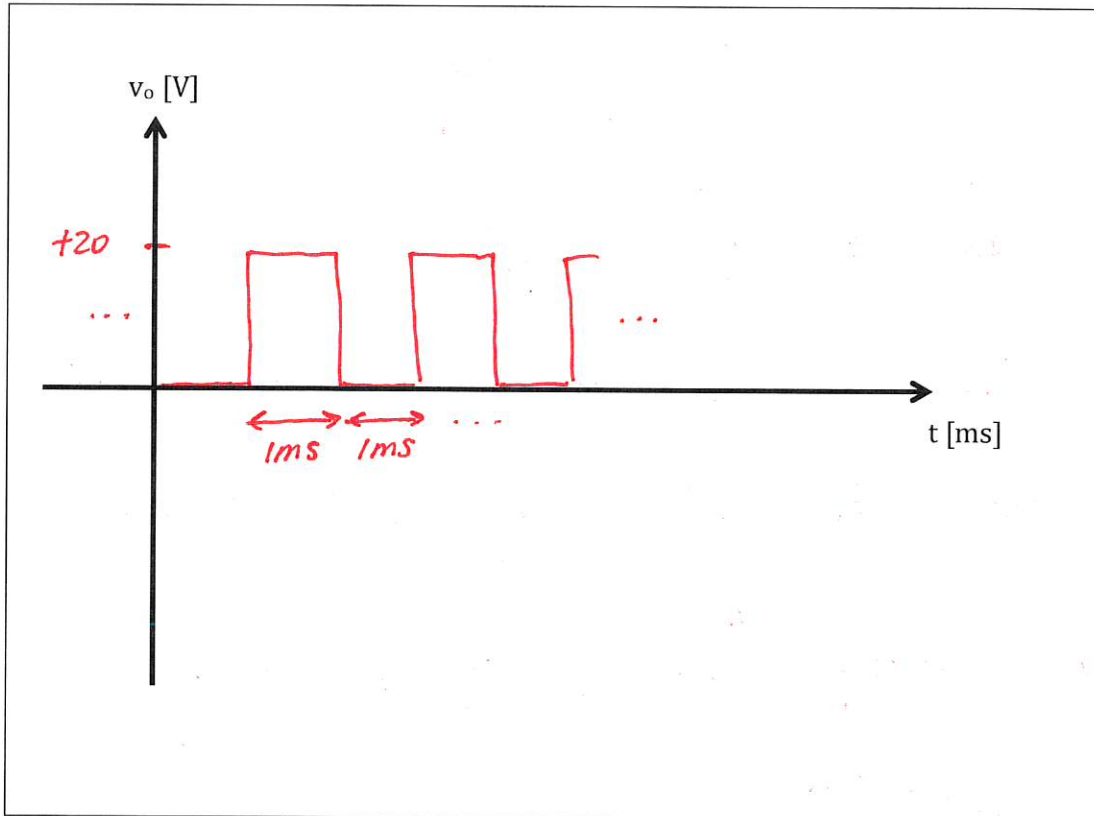


Figure 3.



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Problem 6 [20 pts]

In the following circuit assuming  $\mu_n C_{ox} = 100 \mu\text{A}/\text{V}^2$  and  $V_{TH} = 0.4 \text{ V}$  and  $\lambda \approx 0 \text{ V}^{-1}$ , determine the maximum allowable value of  $W/L$  if  $M_1$  must remain in saturation.

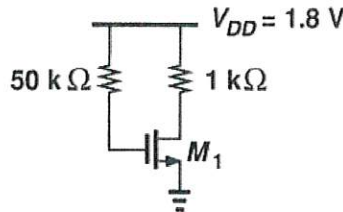


Figure 4.

Assume the current flowing into the gate of the transistor is negligible ( $I_G = 0$ ).

$V_{GS} =$	$V_{DD} = 1.8 \text{ V}$
$W/L \leq$	4

$$I_D = \frac{\mu C_{ox}}{2} \frac{W}{L} (V_{GS} - V_{TH})^2$$

$$V_{DS} \geq V_{GS} - V_{TH} \quad \text{for } M_1 \text{ to remain in sat.}$$

$$V_{DS} = V_{DD} - R_D I_D = V_{DD} - R_D \frac{\mu C_{ox}}{2} (V_{GS} - V_{TH})^2 \frac{W}{L}$$

$$1.8 - 1\text{k} \cdot \frac{100 \mu}{2} (\cancel{1.8} - 0.4)^2 \frac{W}{L} \geq \cancel{1.8} - 0.4$$

~~$\frac{W}{L} \leq \frac{0.4}{50 \times 10^{-3} \times 1.4^2} = \frac{0.4}{98 \times 10^{-3}} \approx 4$~~

$$1.8 - 50 \times 10^{-3} \times 1.4^2 \cdot \frac{W}{L} \geq -0.4$$

$$\frac{W}{L} \leq \frac{0.4}{50 \times 10^{-3} \times 1.4^2} = \frac{0.4}{98 \times 10^{-3}} \approx 4$$